Substitute for Form 1449 A & B/PTO	Complete if Known			
Substitute for Forth 1449 A & BJF 10	Application Number	10/813,269		
ANFORMATION DISCLOSURE	Confirmation Number	5356		
STATEMENT BY APPLICANT	Filing Date	March 31, 2004		
JUH 3 0 2004 2	First Named Inventor	Lawrence SHAH		
(use as many sheets as necessary)	Art Unit	2828		
	Examiner Name	Not yet assigned		
reet 1 of 4	Attorney Docket Number	A8700		

U.S. PATENT DOCUMENTS								
E	Cite	Document	Number	Publication Date				
Examiner Initials*	No.1	Number	Kind Code ² (if known)	MM-DD-YYYY	Name of Patentee or Applicant of Cited Document			
DW		US 5,720,894	A	02-24-1998	Neev et al.			
		US 5,978,538	Α	11-02-1999	Miura et al.			
\Box		US 6,146,375	Α	11-14-2000	Juhasz et al.			
		US 6,268,586	B1	07-31-2001	Stuart et al.			
		US 6,285,002	Bl	09-04-2001	Ngoi et al.			
		US 6,312,768	B1	11-06-2001	Rode et al.			
		US 6,333,485	Bl	12-25-2001	Haight et al.			
		US 6,392,683	B1	05-21-2002	Hayashi			
-,/		US 6,407,361	B1 .	06-18-2002	Williams			

			F	OREIGN PA	TENT DOCUMEN	NTS	
Examiner	Cite	Foreign Patent Document		ment	Publication Date	Name of Patentee or	
Initials*	No.1	Country Code ³	Number ⁴	Kind Code ⁵ (if known)	MM-DD-YYYY	Applicant of Cited Document	Translation ⁶
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		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
DM		Manufacturing of High Quality Integrated Optical Components by Laser Direct-Write (M103) Ph. Bado, A. A. Said, Mark Dugan, Translume, 755 Phoenix Drive, Ann Arbor, Michigan 48108	
١		A Study of the Effect of Weld Parameters on Strengths of Clearwelded TM Thermoplastics (602) Nicole M. Woosman and Michelle M. Burrell Gentex Corporation Carbondale, Pennsylvania, USA	
		Writing of permanent birefringent microlayers in bulk fused silica with femtosecond laser pulses L. Sudrie, M. Franco, B. Prade, A. Mysyrowicz* Received 9 August 1999; accepted 22 September 1999	
		Burst-mode femtosecond ablation in Copper and Lexan Craig W. Siders, Martin Richardson, Nikolai Vorobiev, Ty Ohlmstead, Rob Bernath, and Tina Shih The School of Optics/CREOL, University of Central Florida, Orlando Florida 32816-2700	
		Femtosecond Laser Fabricated Nanostructures in Silica Glass R.S. Taylor, C. Hnatovsky, E. Simova, Institute for Microstructural Sciences, National Research Council; D.M. Rayner, V. R. Bhardwaj and P.B. Corkum Steacie Institute for Molecular Sciences, National Research Council	
V		Femtosecond laser ablation of silicon-modification thresholds and morphology J. Bonse", S. Baudach, J. Kruger, W. Kautek, M. Lenzner Laboratory for Thin Film Technology, Federal Institute for Materials Research and Testing (BAM), Unter den Eichen 87, 12205 Berlin Germany, Received 4 Dec. 2000/Revised version: 29 March 2001/Published online: 20 June 2001 - @ Springer-Verlag 2001	

Francisco Singator	m	Date Considered 6/15/06
Examiner Signature		Date Considered /

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ³Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to indicate here if English language Translation is attached.

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				First Named Inventor	Lawrence SHAH
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U.S. PATENT DOCUMENTS							
		Document Nu	mber				
Examiner Cite Initials* No.		Number Kind Code ² (if known)		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		
טע		US 6,421,573	B1	07-16-2002	Kfka et al.		
		US 6,552,301	B2	04-22-2003	Herman et al.		
		US 6,573,026	B1	06-03-2003	Aitken et al.		
		US 6,574,250	B2	06/03/2003	Sun et al		
		US 2003/0035640	A1	02/20/2003	Dugan et al		
		US 2003/0099452	A1	05/29/2003	Borrelli et al		
		US 2003/0110810	A1	06/19/2003	Dunn et al		
1/7		US 2002/0076655	A1	06/20/2002	Borrelli et al		
- V		US 2002/0193704	Al	12/19/2002	Goldstein et al		

			F	OREIGN PA	TENT DOCUM	ENTS	
Examiner	Cite	Foreign Patent Document		Publication Date	Name of Patentee or	m1-4'6	
Examiner Initials*	No.¹	Country Code ³	Number ⁴	Kind Code ⁵ (if known)	MM-DD-YYYY	Applicant of Cited Document	Translation*
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or		Femtosecond writing of active optical waveguides with astigmatically shaped beams Roberto Osellame, Stefano Taccheo, Marco Marangoni, Roberta Ramponi, and Paolo Laporta, Dario Polli, Sandro De Silvestri, and Giulio Cerullo, Received November 19, 2002; revised manuscript received February 7, 2003	
		Laser Welding of Plastics - Process Selection Software (601) Ian Jones and Sam Rostami Polymer Group, TWI, Cambridge UK	
	,	Proceedings of the International Tribology Conference Nagasaki, 2000 MICROTEXTURING OF FUNCTIONAL SURFACES FOR IMPROVING THEIR TRIBOLOGICAL PERFORMANCE Henry HAEFKE, Yvonne GERBIG, Gabriel DUMITRU and Valerio ROMANO	
		New low temperature femto-second laser annealing method for TFT fabrication technology Alexei K. Zaitsev, Yi-Chao Wang and Ci-Ling Pan; Jia-Min Shieh	
/		Processing of multi-layer systems using femtosecond, picosecond, and nanosecond lasaer pulses at different wavelengths David Ashkenasi*, Arkadi Rosenfeld** Laser-und Medizin-Technologie GmbH Berlin, Germany; Max Born Berlin, Germany	
V		Ripples revisted: non-classical morphology at the bottom of femtosecond laser ablation craters in transparent dielectrics Jurgen Reif*, Florenta Costache, Matthias Henyk, Stanislav V. Pandelov	

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Substitute for Form 1449	A & R/PTO			Complete if Known			
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U.S. PATENT DOCUMENTS							
	Cite	Document N	vumber	Publication Date			
Examiner Initials*	No.1	Number	I Kind Code* I		Name of Patentee or Applicant of Cited Document		
1)4		US RE37,585	E	03/19/2002	Mourou et al		
ī		US 6,372,103	B1	04/16/2002	Perry et al		
-1.1		US 6,414,320	B1	07/02/2002	Ishikawa et al		
1/		US 6,341,009	B1	01/22/2002	O'Connor et al		
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	FOREIGN PATENT DOCUMENTS							
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		NON PATENT LITERATURE DOCUMENTS	
Examiner Initials*	Cite No.1	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city, and/or country where published.	Translation ⁶
DW		CWI1 Self-organized form birefringence in glass irradiated by intense ultrashort light pulses P.G. Kazansky, J. Mills, E. Bricchi, J.J. Baumberg, J. Qiu and K. Hirao	
		CFF2 Single-pulse and 'pulsetrain-burst' (>100 MHz) effects in ultrafast laser processing of metals, glasses, and bio-tissues Santiago Camacho-Lopez, Rodger Evans, Catherine Greenhalgh, Cristian Torti, John Robertson, Robin Marjoribanks, Peter Herman, Marc Nantel, Lothar Lilge	
		Proc. SPIE Vol. 4274 STRUCTURING SILICON WITH FEMTOSECOND LASERS H.K. Tonshoff, A. Ostendorf, T. Wagner Laser Zentrum Hannover e. V. (www.lzh.de), Hollerithallee 8, D-30419 Hannover, Germany	
		Optics Communications 191 (2001) 333-339 Study of damage in fused silica induced by ultra-short IR laser pulses L. Sudrie, M. Franco, B. Prade, A. Mysyrowicz* Received 15 January 2001; accepted 28 February 2001	
		Applied Physics Letters, Volume 82, Number 17, 28 April 2003, Surface nanostructuring of borosilicate glass by femtosecond nJ energy pulses	
V		Ultra-fast laser-induced processing of materials: fundamentals and applications in micromachining Tae Y. Choi, Anant Chimmalgi and Constantine P. Grigoropoulos Department of Mechanical Engineering, University of California, Berkeley	

Examiner Signature Date Considered 6/15/06
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¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ³Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to indicate here if English language Translation is attached.

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NON PATENT LITERATURE DOCUMENTS					
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DW	,	Ultrafast pulse train micromachining Ihtesham H. Chowdhury, Xianfan Xu, Andrew M. Weiner, School of Mech. Engg., Purdue Univ., W. Lafayette, IN, USA 47907-1288 School of Elec. and Comp. Engg., Purdue Univ., W. Lafayette, IN, USA 47907-1285			
1)V		Ultra-High Resolution Index of Refraction Profiles of Femtosecond Laser Modified Silica Structures, R.S. Taylor, C. Hnatovsky, E. Simova, D.M. Rayner, V.R. Bhardwaj and P.B. Corkum Abstract: Ultra-high spatial resolution index of refraction profiles of femtosecond laser modified structures in silica glass			

Examiner Signature Date Considered 6/15/06

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¹Applicant's unique citation designation number (optional). ²See Kind Codes of USPTO Patent Documents at www.uspto.gov, MPEP 901.04 or in the comment box of this document. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST. 3). ⁴For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ²Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to indicate here if English language Translation is attached.

Substitute for Form 1449 A & B/PTO INFORMATION DISCLOSURE

STATEMENT BY APPLICANT

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Sheet	1.	of	4

Сотр	Complete if Known					
Application Number	10/813,269					
Confirmation Number	5356					
Filing Date	March 31, 2004					
First Named Inventor	Lawrence SHAH					
Art Unit	2828					
Examiner Name	Dung T. NGUYEN					
Attorney Docket Number	A8700					

			U.S. 1	PATENT DOCU	MENTS
Examiner Initials*	Cite No. ¹	Document Nu Number	mber Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document
0~0		US RE37,585	E	03/19/2002	Gerard Mourou
1		US 6,333,485 `	Bl	12/25/2001	Richard Alan Haight
· []		US 6, 268,586	Bl	07/31/2001	Brent C. Stuart
		US 5,720,894		02/24/1998	Joseph Neev
		US 6,552,301	B2	04/22/2003	Peter R. Herman
		US 6,574,250	B2	06/03/2003	Yunlong Sun
		US 6,421,573	B1	07/16/2002	James D. Kafka
		US 6,285,002	Bl	09/04/2001	Bryan Kok Ann Ngoi
		US 2002/0023903		02/28//2002	Bryan Kok Ann Ngoi
		US 6,341,009	Bi	01/22/2002	John O'Connor
		US 6,146,375		11/14/2000	Tibor Juhasz
		US 2002/0193704	A1	12/19/2002	Peter Goldstein
		US 6,414,320	Bi	07/2/2002	Muriel Y. Ishikawa
		US 5,978,538		11/2/1999	Kiyotaka Miura
		US 2002/0076655	Al	06/20/2002	Nicholas F. Borrelli
		US 2003/0099452	A1	05/29/2003	Nicholas F. Borrelli
		US 2003/0035640	A1	02/20/2003	Mark Dugan
		US 6,573,026	BI	06/3/2003	Bruce G. Aitken
1/		US 2003/0110810	Al	06/19/2003	Douglas Scott Dunn
1//		US 6,392,683	Bl	05/21/2002	Kenichi Hayashi
V		US 6,407,361		06/18/2002	Mark S. Williams

FOREIGN PATENT DOCUMENTS								
Examiner		Foreign Patent Document			Publication Date	Name of Patentee or		
lnitials*		Country Code ³	Number ⁴	Kind Code ⁵ (if known)	MM-DD-YYYY	Applicant of Cited Document	Translation*	

	NON PATENT LITERATURE DOCUMENTS					
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DW		Tae Y. Choi, "Ultra-fast laser-induce processing of materials: fundamentals and applications in micromaching." SPIE Proceedings Vol 4637 (2002) pp. 204-211				
^		Ihtesham H. Chowdhury, "Ultrafast pulse train micromaching," Spie Proceedings Vol 4978 (2003) pp. 138-146				
		Santiago Camacho-Lopez, "Single-pulse and 'pulsetrain-burst' (>100MHz) effects in ultrafast laser processing of metals, glasses, and bio-tissues" OSA CLEO 2003 in Baltimore, MD (May) Paper CFF2				

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Complete if Known Substitute for Form 1449 A & B/PTO INFORMATION DISCLOSURE 10/813,269 **Application Number** Confirmation Number 5356 STATEMENT BY APPLICANT March 31, 2004 Filing Date First Named Inventor Lawrence SHAH 2828 (use as many sheets as necessary) Art Unit **Examiner Name** Dung T. NGUYEN Sheet Attorney Docket Number A8700

	U.S. PATENT DOCUMENTS						
		Document N	umber				
Examiner Initials*	Cite No. ¹	Number	Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		
DV		US 6,312,768		11/6/2001	Andrei Rode		
07		US 6,372,103	B1	4/16/2002	Michael D. Perry		
		US					

			F	OREIGN PA	TENT DOCUME	NTS	
Examiner	Cite	Foreign Patent Document		Publication Date	Name of Patentee or		
Initials*	No.1	Country Code ³	Number ⁴	Kind Code ⁵ (if known)	MM-DD-YYYY	Applicant of Cited Document	Translation ⁶
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DV		Craig W. Siders, "Burst-mode femtosecond abltion in Copper and Lexan" OSA CLEO 2003 in Baltimore, MD (May) paper CFF3	
1		L. Sudrie, "Writing of permanent birefringement microlayers in bulk fused silica with femtosecond laser pulses" Optics Communications 171 (1999) 279-284	
		Roberto Osellame, "Femtosecond writing of active optical waveguides with astigmatically shaped beams" J. Opt. Soc. Am. B Vol. 20 No 7/ July 2003 p 1559-1567	
		John D. Mills, "Embedded anisotropic microreflectors by femtosecond-laser nanomachining" Applied Physics Letters Vol. 81, No. 2 July 2002, p196-198	
		A. Bado, "Manufacturing of High quality Integrated Optical Components by Laser Direct-Write (M103) ICALEO 2003 in Jacksonville, FL. Laser Microfabrication, LMF Section C p 18-26	
		L. Sudrie, "Study of damage in fused silica induced by ultra-shor IR laser pulses" Optics Communications 191 (2001) 333-339	
		P. G. Kazansky, "Self-organized form birefringence in glass irradiated by intense ultrashort light pulses" OSA CLEO 2003 in Baltimore, MD (May) paper CWI1	
		Henry Haefke, "Microtexturing of functional surfaces for improving their tribological performance" Proceeding of the International Tribology Conference, Nagasaki, 2000 p 217-221	
		H.K. Tonshoff, "Structuring silicon with femtosecond lasers," SPIE Proceedings Vol. 4274 (2001) p 88-97	
		J.Bonse, "Femtosecond laser ablation of silicon-modification thresholds and morphology," Applied Physics A 74, 19-25, (2002)	
V		Jurgen Reif, "Ripples revisited: non-classical morphology at the bottom of femtosecond laser ablation craters in transparent dielectrics," Applied Surface Science 197-198 (2002) 891-895	

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INFORMATION DISCLOSURE

STATEMENT BY APPLICATIONAL (use as many sheets as necessary)

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FOREIGN PATENT DOCUMENTS							
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		NON PATENT LITERATURE DOCUMENTS	
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DV		Egidijus Vanagas, "Surface nanostructuring of borosilicate glass by femtosecond nJ energy pulses," Applied Physics Letters Vol.82, No. 17, 28 April 2003, p.2901-2903	
\$c.		R.S. Taylor, "Femtosecond Laser Fabricated Nanostructures in Silica Glass," OSA CLEO 2003 in Baltimore, MD (May). Paper CWA18	
		R.S. Taylor, "Ultra-High Resolution Index of Refraction Profiles of Femtosecond Laser Modified Silica Structures," OSA CLEO 2003 in Baltimore, MD (May). Paper CWI3	
	-	David Ashkenasi, "Processing of multi-layer systems using femtosecond, picosecond, and nanosecond laser pulses at different wavelengths," SPIE Proceedings Vol. 4637 (2002) p169-179	
		Alexei K. Zaitsev, "New low temperature femto-second laser annealing method for TFT fabrication technology," OSA CLEO 2003 in Baltimore, MD (May). Paper CThM34	
		lan Jones, "Laser Welding of Plastics-Process Selection Software (601) ICALEO 2003 in Jacksonville, FL. Laser Materials Processing LMP Section A p 76-84	
		Ian Jones, "Laser Welding of Plastics-Process Selection Software (601) ICALEO 2003 in Jacksonville, FL. Laser Materials Processing LMP Section A p 76-84	
		Nicole M. Woosman, "A Study of the Effect of Weld Parameters on Strengths of Clearwelede Thermoplastics (602) ICALEO 2003 in Jacksonville, FL. Laser Materials Processing, LMP Section A p 85-93	
		Kulik et al, Short and ultrashort laser pulses: an upcoming tool for processing optical and semiconductor materials, Proc. SPIE Int. Soc. Opt. Eng. 5339, 35 (2004)	
		Said et al, Manufacturing by laser direct-write of three-dimensional devices containing optical and microfluidic networks, Bado, Said, Dugan, Translume, Proc. SPIE Int. Soc. Opt. Eng. 5339, 194 (2004)	
		Ostendorf et al, Ablation of metals and semiconductors with ultrashort pulsed lasers: improving surface qualities of microcuts and grooves, Proc. SPIE Int. Soc. Opt. Eng. 5340, 153 (2004)	
		Watanabe et al, Fabrication of photonic devices with femtosecond laser pulses, Proc. SPIE Int. Soc. Opt. Eng. 5340, 119 (2004)	
V^{-1}		Femtosecond laser machining of integrated capillaries in microfludic devices, Tyson N. Kim Photonics West Poster Session 5340-31 Only, no paper submitted	

Examiner Signature	m	Date Considered	6/15/01

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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MODIFIED PTO/SB/08 A & B (08-03) Complete if Known Substitute for Form 1449 A & B/PTO 10/813,269 **Application Number** Confirmation Number 5356 INFORMATION DISCLOS March 31, 2004 Filing Date STATEMENT BY APPLICANT First Named Inventor Lawrence SHAH (use as many sheets as necessary) Art Unit 2828 Dung T. NGUYEN **Examiner Name** Sheet 4 of 4 **Attorney Docket Number** A8700

U.S. PATENT DOCUMENTS							
Francisco	Cite	Document	Number	Publication Data			
Examiner Initials*	No.1	Number	Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		
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		NON PATENT LITERATURE DOCUMENTS	
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0~		A. Ostendorf et al, "Abalation of metals and semiconductors with ulstrashort-pulsed lasers: improving surface qualities of microcuts and grooves", Proc., SPIE vol 5340 (2004) pp. 153-163	
此		W. Watanabe et al, "Fabrication of photonic divices with femtosecond laser pulses", Proc SPIE, vol 5340 (2004) pp. 119-126	
		A. Said et al, "Manufacturing by laser direct-write of three-dimensional devices containing optical and microfluidic networks", Proc SPIE vol. 5339 (2004) pp. 194-204	
V		C. Kulik, "Short and Ultrashor t Laser Pulses: An upcoming Tool for Processing Optical and Semiconductor Materials", Proc. SPIE vol. 5339 (2004) pp. 35-48	

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Examiner	Cite	Do	mber	P	Publication Date MM-DD-YYYY 01/12/1988		le				
Initials*	No.1	Number		Kind Co			ie' i M				
mw't		US 4,718,417		(if know				Kittrell et al			
		US 2003/0156605		Al		08/21/2003		Richardson et al			
		US 2003/0025911		Al		02/02/2003		Walmsley et al			
		US 6,327,063		BI		12/04/2001		Rockwell			
		US 5,609,780				03/11/1997		Freedenberg et al			
V		US 2002/0071901		Al		07/13/2002		Ringeisen et al			
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